TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

# **TPCS8204**

Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance:  $R_{DS}$  (ON) = 13 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 15 \text{ S} (typ.)$
- Low leakage current:  $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 20 \ V)$
- Enhancement-mode:  $V_{th} = 0.5 \sim 1.2 \text{ V} (V_{DS} = 10 \text{ V}, \text{ID} = 200 \text{ }\mu\text{A})$

### Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	20	V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	20	V	
Gate-source voltage		V <sub>GSS</sub>	±12	V	
Drain current	DC (Note 1)	I <sub>D</sub>	6	А	
Drain current	Pulse (Note 1)	$\begin{array}{c c c c c c c c } \hline V_{DSS} & 20 \\ \hline V_{DSS} & 20 \\ \hline V_{DSS} & 20 \\ \hline V_{QSS} & \pm 12 \\ \hline & V_{GSS} & \pm 12 \\ \hline & V_{GSS} & \pm 12 \\ \hline & V_{OSS} & \pm 12 \\ \hline$	~		
Drain power dissipation	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.1		
(t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.75	W	
Drain power dissipation (t = 10 s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.6		
	Single-device value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.35	W	
Single pulse avalanche energy (Note 4)		E <sub>AS</sub>	46.8	mJ	
Avalanche currei	nt	I <sub>AR</sub>	6	А	
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E <sub>AR</sub>	0.075	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 0.035 g (typ.)

# **Circuit Configuration**



Note: For (Note 1), (Note 2), (Note 3), (Note 4) and (Note 5), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm

# **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
	Single-device operation (Note 3a)	R <sub>th (ch-a)</sub> (1)	114	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	167		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a)</sub> (1)	208		
(t = 10  s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	357	°C/W	

## Marking (Note 6)





Note 2:

a) Device mounted on a glass-epoxy board (a)







#### Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device. (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device. (During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD} = 16 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}$  (initial), L = 1.0 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = 6 A

- Note 5: Repetitive rating; pulse width limited by maximum channel temperature
- Note 6: on lower left of the marking indicates Pin 1.



Electrical Characteristics (Ta = 25°C)

Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS}=\pm 10~V,~V_{DS}=0~V$		_	±10	μA
Drain cut-OFF current		I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	_	10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	20	_	_	V
Diam-source bie	andown voltage	V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8	_	_	v
Gate threshold ve	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 200 \mu\text{A}$	0.5	_	1.2	V
Drain-source ON resistance			$V_{GS} = 2.0 \text{ V}, \text{ I}_{D} = 4.2 \text{ A}$	_	24	35	mΩ
		R <sub>DS (ON)</sub>	$V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 4.2 \text{ A}$	_	18	22	
			$V_{GS} = 4.0 \text{ V}, \text{ I}_{D} = 4.8 \text{ A}$	_	13	17	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 3.0 \text{ A}$	7.5	15	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		2160	_	pF
Reverse transfer capacitance		C <sub>rss</sub>			210		
Output capacitance		C <sub>oss</sub>			230	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} \begin{array}{c} 5 \\ 0 \\ V \\ 0 \\ V \end{array} \right) I_{D} = 3 A$ $V_{OUT}$ $G \\ G \\ G \\ M \\ V \\ M \\ V \\ DD \approx 10 V$ $V_{DUT} = 10 $	_	5	_	- ns
	Turn-ON time	t <sub>on</sub>		_	13	_	
	Fall time	t <sub>f</sub>			10		
	Turn-OFF time	t <sub>off</sub>			53		
Total gate charge (gate-source plus gate-drain)		Qg			22		
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD} \simeq 16 \text{ V}, \text{ V}_{GS} = 5 \text{ V}, \text{ I}_{D} = 6 \text{ A}$	_	4	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			5	_	

# Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	24	А
Forward voltage (diode)		V <sub>DSF</sub>	$I_{DR} = 6 \text{ A}, \text{ V}_{GS} = 0 \text{ V}$			-1.2	V

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Drain current



Drain-source voltage V<sub>DS</sub> (V)

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